


<b>Search Notes</b>  	<b>Application/Control No.</b>  10507419	<b>Applicant(s)/Patent Under Reexamination</b>  BAYER ET AL.
	<b>Examiner</b>  RANDOLPH CHU	<b>Art Unit</b>  2624

SEARCHED			
Class	Subclass	Date	Examiner
382	285	5/24/2007	ric

SEARCH NOTES		
Search Notes	Date	Examiner
EAST	5/24/2007	ric
Inventor Name Search	5/24/2007	ric
NPL, Internet	5/24/2007	ric
Consult with Wenpeng Chen	5/24/2007	ric
Updated East Search	6/10/2008	ric
Consult with Wenpeng Chen	6/10/2008	ric
Consult with Andy Johns	6/10/2008	ric

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner